Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10725352	ROUVELLOU ET AL.
Examiner	Art Unit
Fernández Rivas, Omar F	2129

SEARCHED					
Class	Subclass	Date	Examiner		
706	16,19,45-48,903,919,922	8/28/2008	OFR		
717	100-106,117,142	8/28/2008	OFR		
700	90,103,104	8/28/2008	OFR		
705	1,7-11	8/28/2008	OFR		

SEARCH NOTES			
Search Notes	Date	Examiner	
EASTsearch update-all databases. Keywords: rule, author, template, vocabulary, language, term	8/28/2008	OFR	
Inventor nane search: Isabelle M. Rouvellou, Hoi Y. Chan, Louis R. Degenaro, Judah M. Diament, Achille B. Fokoue-Nkoutche, Charles A. Kerr JR., Mark H. Linehan, Arvind Rajpurohit, Samuel M. Weber	8/28/2008	OFR	
Class 706, subclasses: 16,19,45-48,903,919,922. Search limited as shown in attached documents.	8/28/2008	OFR	
Class 717, subclasses: 100-106,117,142. Search limited as shown in attached documents.	8/28/2008	OFR	
Class 700, subclasses 90, 103, 104. Search limited as shown in attached documents.	8/28/2008	OFR	
Class 705, subclasses 1,7-11. Search limited as shown in attached documents.	8/28/2008	OFR	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
706	45-47	8/28/2008	OFR	
717	108	8/28/2008	OFR	
705	1	8/28/2008	OFR	
EAST-US PGPUB	(vocabulary and language and term and template).clm.	8/28/2008	OFR	

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